



Description

JMT N And P-Channel Enhancement Mode MOSFET

Features

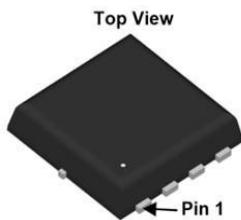
- N-Channel: 40V, 14A
 $R_{DS(ON)} < 22m\Omega @ V_{GS} = -10V$
 $R_{DS(ON)} < 28m\Omega @ V_{GS} = -4.5V$
- P-Channel: -40V, -14A
 $R_{DS(ON)} < 50m\Omega @ V_{GS} = -10V$
 $R_{DS(ON)} < 70m\Omega @ V_{GS} = -4.5V$
- Excellent Gate Charge x $R_{DS(ON)}$ Product(FOM)
- Very Low On-resistance $R_{DS(ON)}$
- Fast Switching Speed

Application

- Battery Protection
- Load Switch
- Power Management

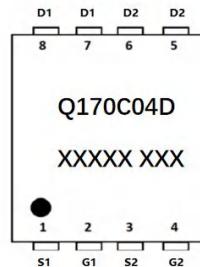


100% UIS TESTED!
100% ΔV_{ds} TESTED!



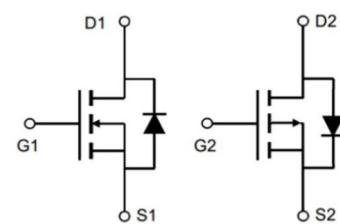
Top View

Bottom View



PDFN3x3-8L-D

Marking and pin Assignment



Schematic Diagram

Package Marking and Ordering Information

Device Marking	Device	OUTLINE	Device Package	Reel Size	Reel (PCS)	Per Carton (PCS)
Q170C04D	JMTQ170C04D	TAPING	PDFN3x3-8L-D	13inch	5000	50000

Absolute Maximum Ratings ($T_C=25^\circ C$ unless otherwise specified)

Symbol	Parameter		Max. N-Channel	Max. P-Channel	Units
V_{DSS}	Drain-Source Voltage		40	-40	V
V_{GSS}	Gate-Source Voltage		± 20	± 20	V
I_D	Continuous Drain Current		$T_C = 25^\circ C$	14	-14
			$T_C = 100^\circ C$	9	-9
I_{DM}	Pulsed Drain Current ^{note1}		56	-56	A
E_{AS}	Single Pulsed Avalanche Energy ^{note2}		16	25	mJ
P_D	Power Dissipation	$T_C = 25^\circ C$	7.3	17	W
$R_{\theta JC}$	Thermal Resistance, Junction to Case		17	7.3	$^\circ C/W$
T_J, T_{STG}	Operating and Storage Temperature Range		-55 to +150		$^\circ C$

**N-Channel Electrical Characteristics** ($T_J=25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
Off Characteristic						
$V_{(\text{BR})\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}$, $I_D=250\mu\text{A}$	40	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=40\text{V}$, $V_{GS}=0\text{V}$	-	-	1.0	μA
I_{GSS}	Gate to Body Leakage Current	$V_{DS}=0\text{V}$, $V_{GS}=\pm 20\text{V}$	-	-	± 100	nA
On Characteristics						
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_D=250\mu\text{A}$	1.0	1.5	2.5	V
$R_{DS(\text{on})}$ note3	Static Drain-Source on-Resistance	$V_{GS}=10\text{V}$, $I_D=14\text{A}$	-	16	22	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}$, $I_D=10\text{A}$	-	20	28	$\text{m}\Omega$
Dynamic Characteristics						
C_{iss}	Input Capacitance	$V_{DS}=20\text{V}$, $V_{GS}=0\text{V}$, $f=1.0\text{MHz}$	-	980	-	pF
C_{oss}	Output Capacitance		-	86.2	-	pF
C_{rss}	Reverse Transfer Capacitance		-	68.5	-	pF
Q_g	Total Gate Charge	$V_{DS}=20\text{V}$, $I_D=8\text{A}$, $V_{GS}=10\text{V}$	-	11	-	nC
Q_{gs}	Gate-Source Charge		-	1.9	-	nC
Q_{gd}	Gate-Drain("Miller") Charge		-	2.2	-	nC
Switching Characteristics						
$t_{d(on)}$	Turn-on Delay Time	$V_{DS}=20\text{V}$, $I_D= 14\text{A}$, $R_L=2.5\Omega$, $R_{REN} = 3\Omega$	-	11	-	ns
t_r	Turn-on Rise Time		-	13	-	ns
$t_{d(off)}$	Turn-off Delay Time		-	36	-	ns
t_f	Turn-off Fall Time		-	9	-	ns
Drain-Source Diode Characteristics and Maximum Ratings						
I_S	Maximum Continuous Drain to Source Diode Forward Current	-	-	14	-	A
I_{SM}	Maximum Pulsed Drain to Source Diode Forward Current	-	-	56	-	A
V_{SD}	Drain to Source Diode Forward Voltage	$V_{GS}=0\text{V}$, $I_S= 14\text{A}$	-	-	1.2	V
t_{rr}	Body Diode Reverse Recovery Time	$T_J=25^\circ\text{C}$, $I_F=14\text{A}, dI/dt=100\text{A}/\mu\text{s}$	-	19	-	ns
Q_{rr}	Body Diode Reverse Recovery		-	11	-	nC

Notes:1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

2. EAS condition : $T_J=25^\circ\text{C}$, $V_{DD}=20\text{V}$, $V_{GS}=10\text{V}$, $L=0.5\text{mH}$, $R_g=25\Omega$, $I_{AS}=8\text{A}$ $T_J=25^\circ\text{C}$, $V_{DD}=-20\text{V}$, $V_{GS}=-10\text{V}$, $L=0.5\text{mH}$, $R_g=25\Omega$, $I_{AS}=-10\text{A}$ 3. Pulse Test: Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$

**P-Channel Electrical Characteristics** ($T_J=25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
Off Characteristics						
$V_{(\text{BR})\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$, $I_D = -250\mu\text{A}$	-40	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{\text{DS}} = -40\text{V}$, $V_{\text{GS}}=0\text{V}$	-	-	-1	μA
I_{GSS}	Gate to Body Leakage Current	$V_{\text{DS}}=0\text{V}$, $V_{\text{GS}}= \pm 20\text{V}$	-	-	± 100	nA
On Characteristics						
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}$, $I_D = -250\mu\text{A}$	-1.0	-1.6	-2.5	V
$R_{\text{DS}(\text{on})}$ note3	Static Drain-Source on-Resistance	$V_{\text{GS}}= -10\text{V}$, $I_D = -5\text{A}$	-	38	50	$\text{m}\Omega$
		$V_{\text{GS}}= -4.5\text{V}$, $I_D = -3\text{A}$	-	50	70	
Dynamic Characteristics						
C_{iss}	Input Capacitance	$V_{\text{DS}}= -20\text{V}$, $V_{\text{GS}}=0\text{V}$, $f=1.0\text{MHz}$	-	1034	-	pF
C_{oss}	Output Capacitance		-	107	-	pF
C_{rss}	Reverse Transfer Capacitance		-	79.5	-	pF
Q_g	Total Gate Charge	$V_{\text{DS}}= -20\text{V}$, $I_D = -8\text{A}$, $V_{\text{GS}}= -10\text{V}$	-	20	-	nC
Q_{gs}	Gate-Source Charge		-	3.5	-	nC
Q_{gd}	Gate-Drain("Miller") Charge		-	4.2	-	nC
Switching Characteristics						
$t_{\text{d}(\text{on})}$	Turn-on Delay Time	$V_{\text{DD}}= -20\text{V}$, $I_D = -14\text{A}$, $V_{\text{GS}}= -10\text{V}$, $R_{\text{GEN}}=2.5\Omega$	-	8	-	ns
t_r	Turn-on Rise Time		-	15	-	ns
$t_{\text{d}(\text{off})}$	Turn-off Delay Time		-	23	-	ns
t_f	Turn-off Fall Time		-	9	-	ns
Drain-Source Diode Characteristics and Maximum Ratings						
I_s	Maximum Continuous Drain to Source Diode Forward Current	-	-	-14	-	A
I_{SM}	Maximum Pulsed Drain to Source Diode Forward Current	-	-	-56	-	A
V_{SD}	Drain to Source Diode Forward Voltage	$V_{\text{GS}}=0\text{V}$, $I_s = -14\text{A}$	-	-	-1.2	V
trr	Reverse Recovery Time	$V_{\text{GS}} = 0\text{V}$, $I_s=-14\text{A}$, $dI/dt=100\text{A}/\mu\text{s}$	-	29	-	ns
Q_{rr}	Reverse Recovery Charge		-	20	-	nC

Typical Performance Characteristics-N

Figure 1: Output Characteristics

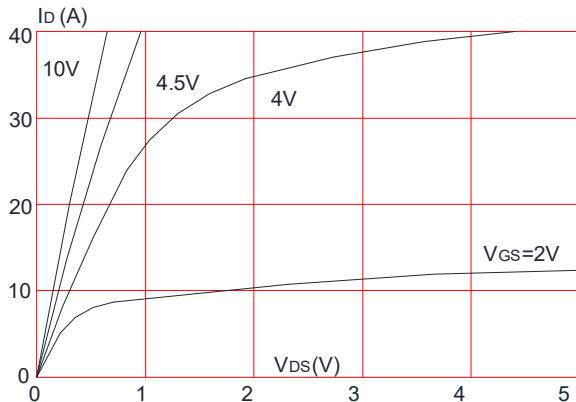


Figure 3: On-resistance vs. Drain Current

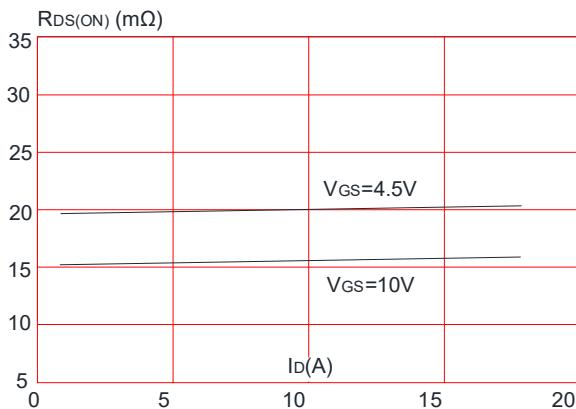


Figure 5: Gate Charge Characteristics

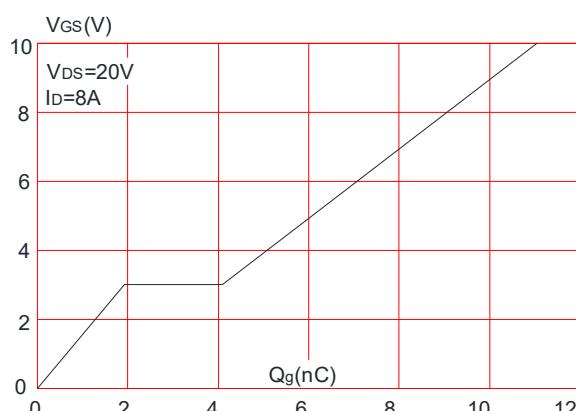


Figure 2: Typical Transfer Characteristics

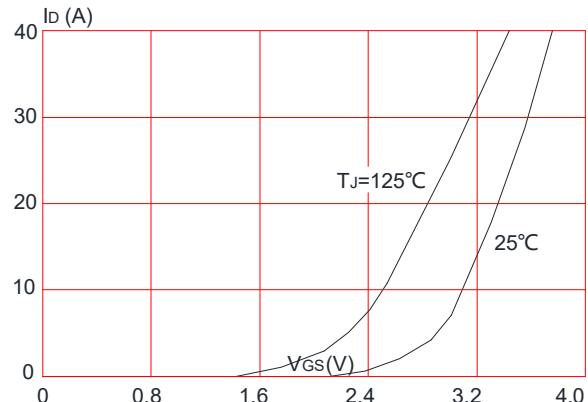


Figure 4: Body Diode Characteristics

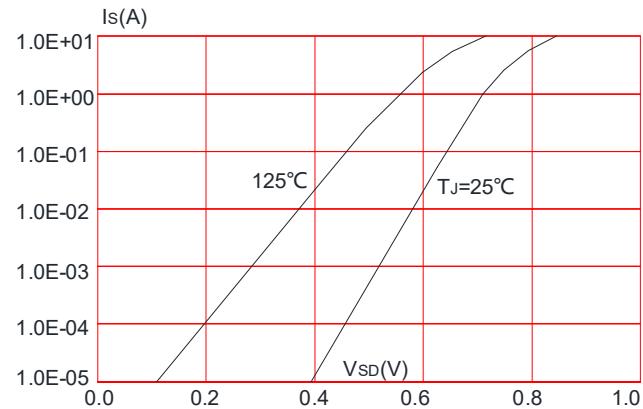


Figure 6: Capacitance Characteristics

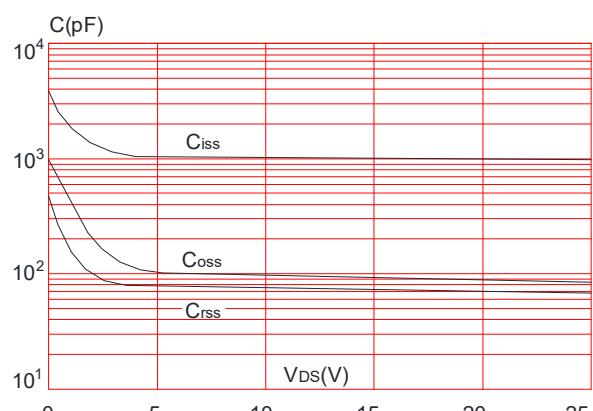


Figure 7: Normalized Breakdown Voltage vs. Junction Temperature

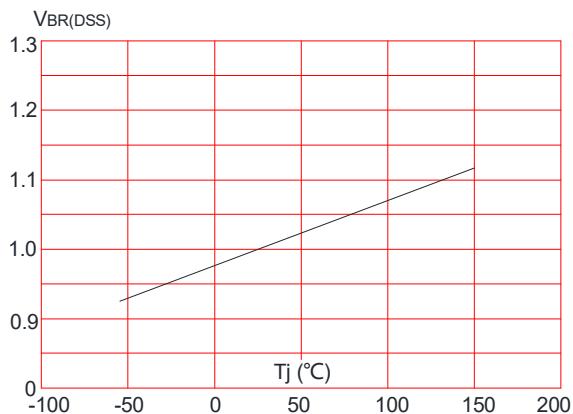


Figure 9: Maximum Safe Operating Area

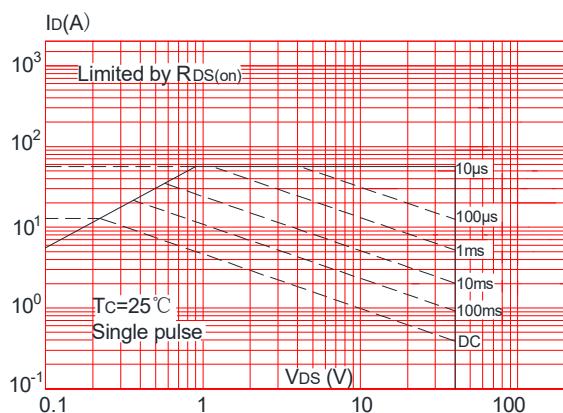


Figure 11: Maximum Effective Transient Thermal Impedance, Junction-to-Case

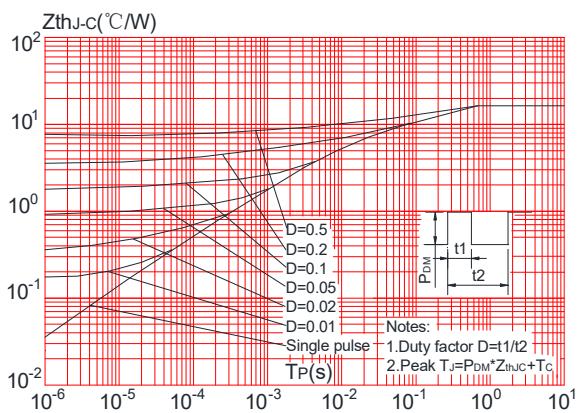


Figure 8: Normalized on Resistance vs. Junction Temperature

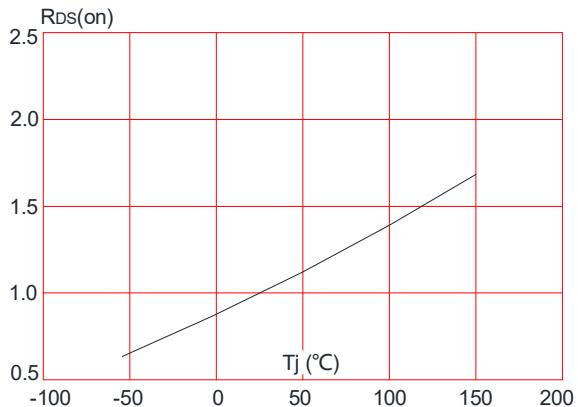
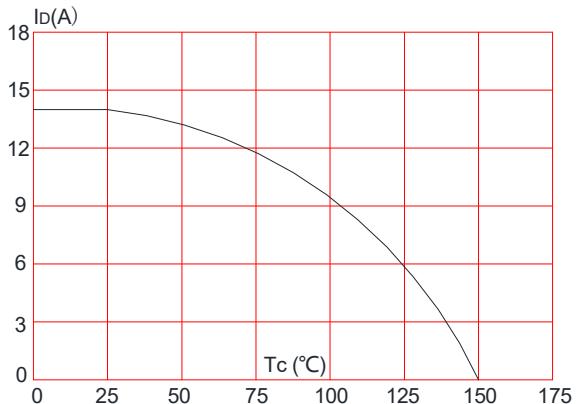


Figure 10: Maximum Continuous Drain Current vs. Case Temperature



Test Circuit-N

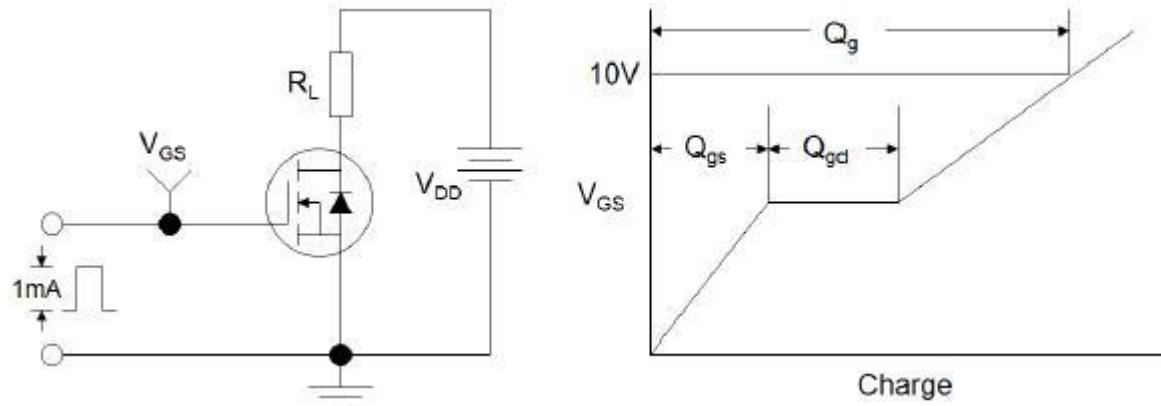


Figure1:Gate Charge Test Circuit & Waveform

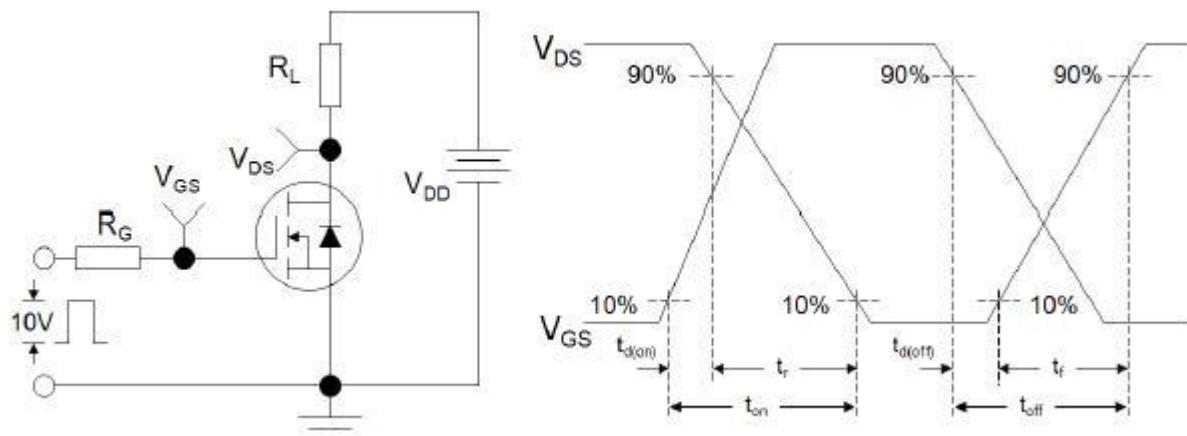


Figure 2: Resistive Switching Test Circuit & Waveforms

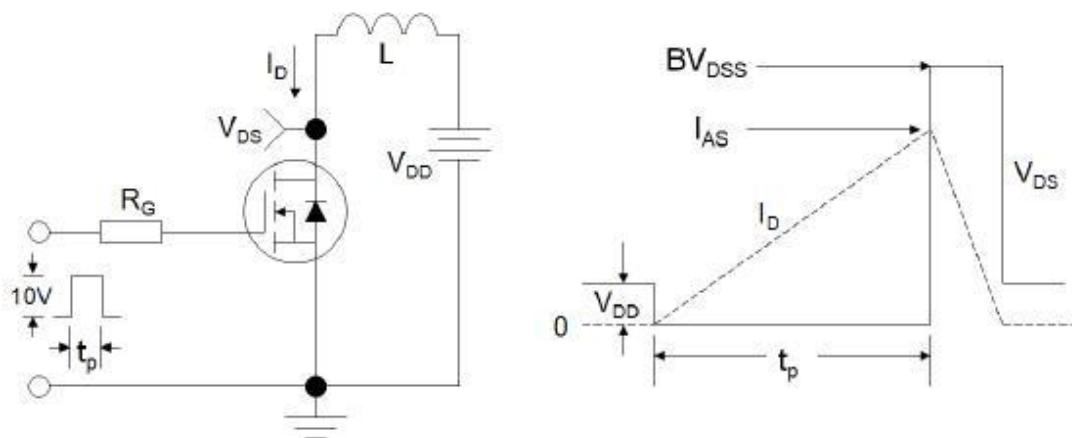


Figure 3:Unclamped Inductive Switching Test Circuit & Waveforms

Typical Performance Characteristics-P

Figure1: Output Characteristics

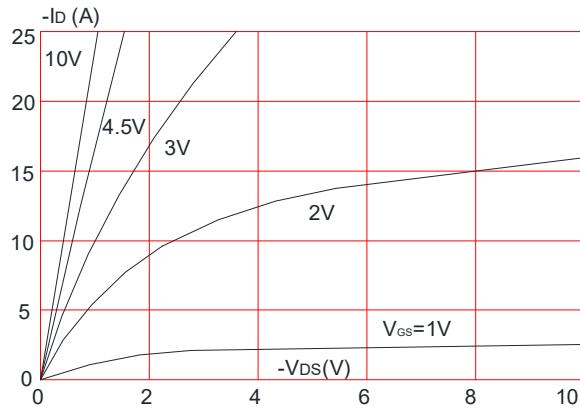


Figure 3: On-resistance vs. Drain Current

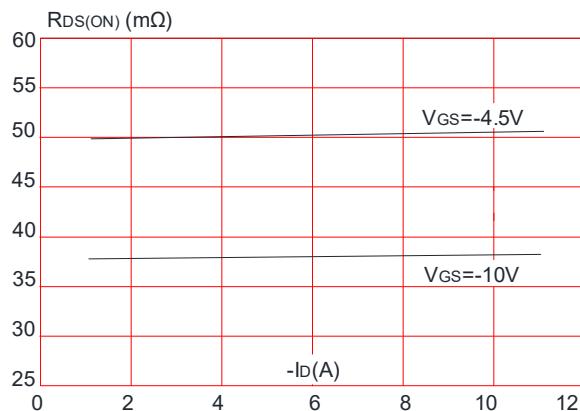


Figure 5: Gate Charge Characteristics

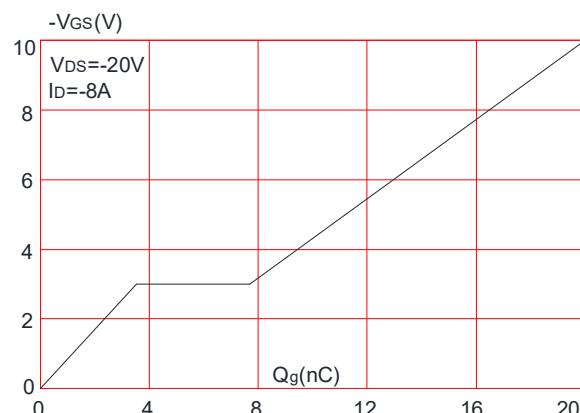


Figure 2: Typical Transfer Characteristics

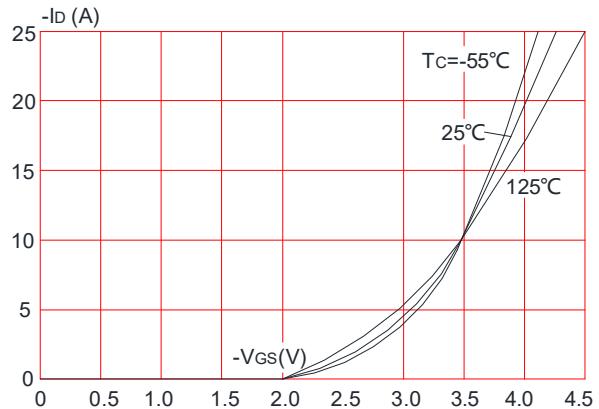


Figure 4: Body Diode Characteristics

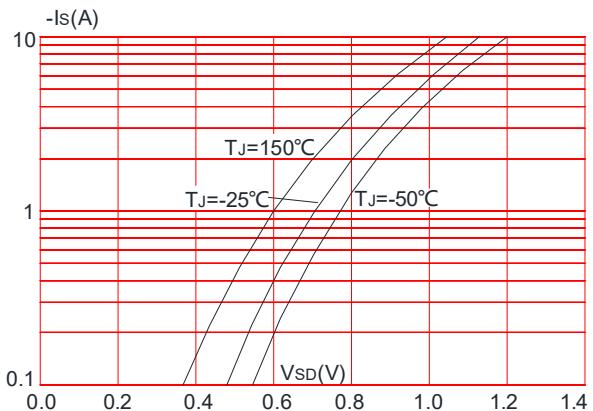


Figure 6: Capacitance Characteristics

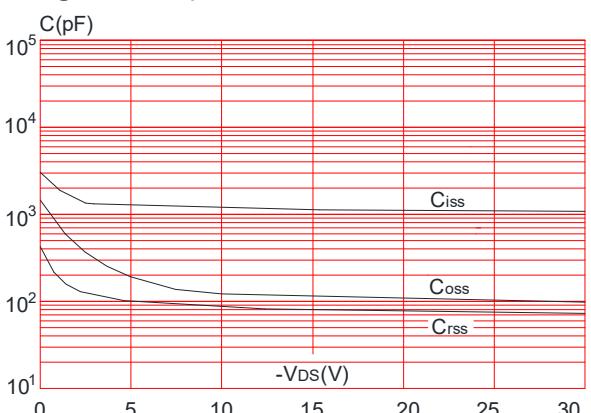


Figure 7: Normalized Breakdown Voltage vs. Junction Temperature

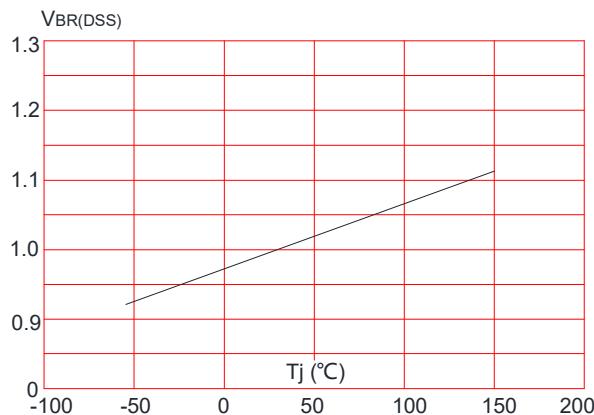


Figure 8: Normalized on Resistance vs. Junction Temperature

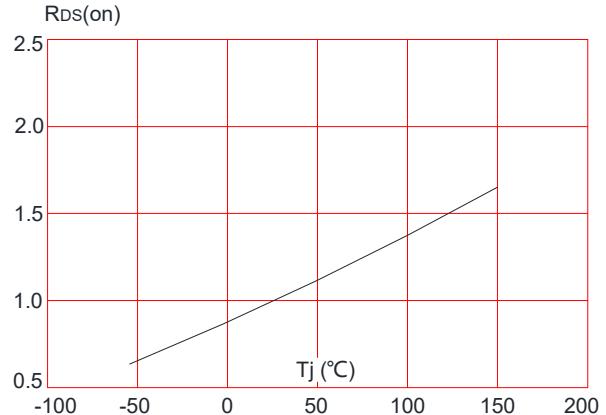


Figure 9: Maximum Safe Operating Area

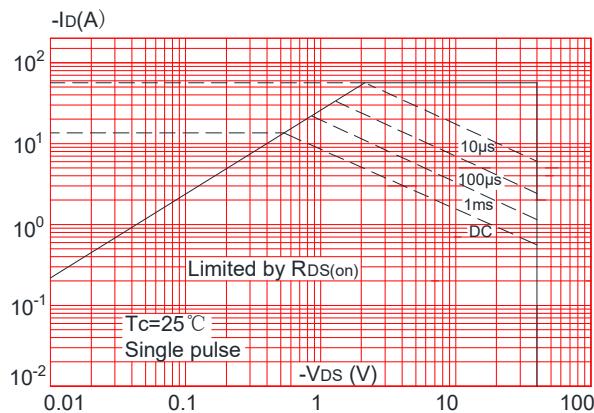


Figure 10: Maximum Continuous Drain Current vs. Case Temperature

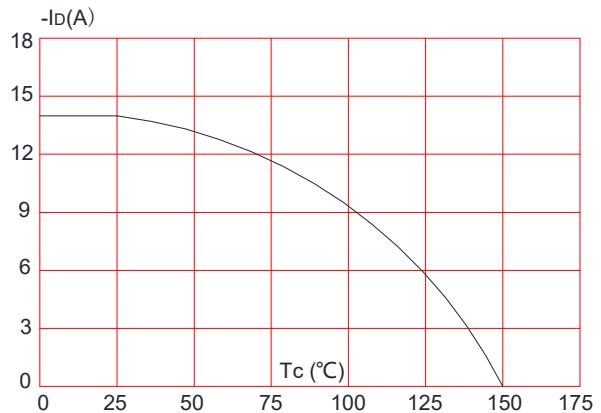
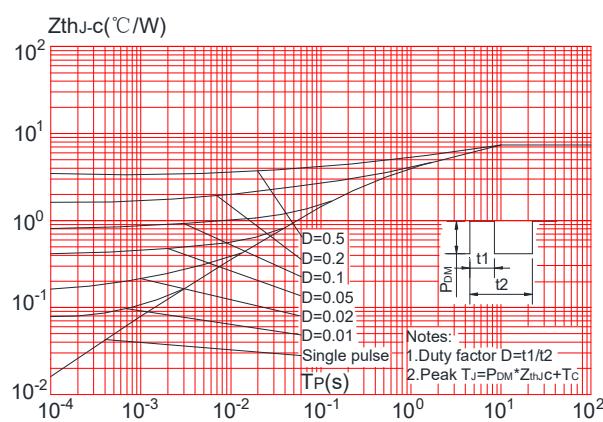
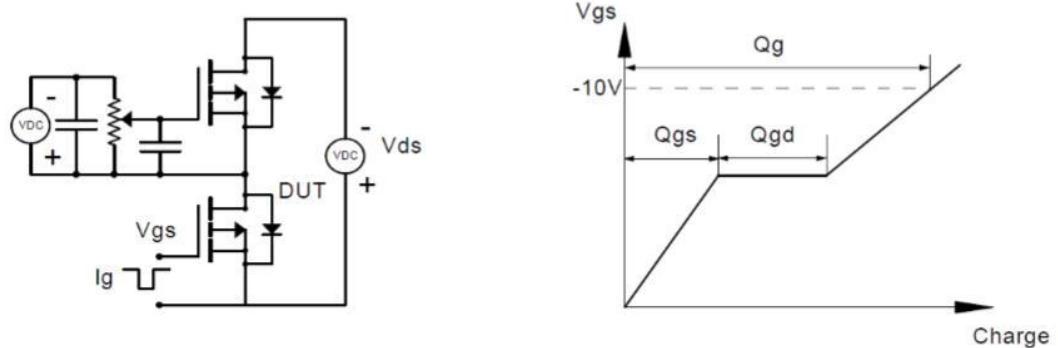


Figure 11: Maximum Effective Transient Thermal Impedance, Junction-to-Case

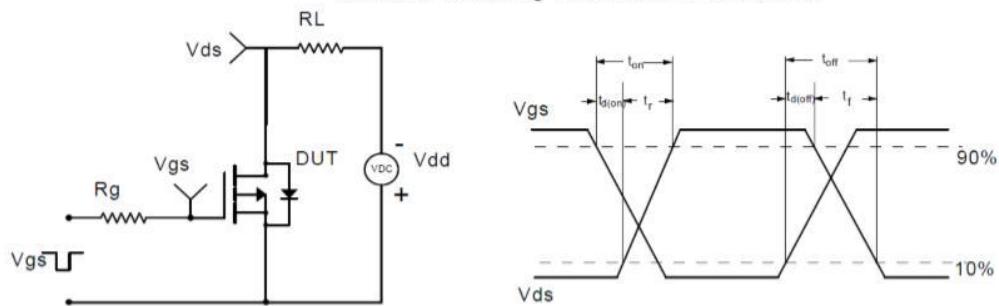


Test Circuit-P

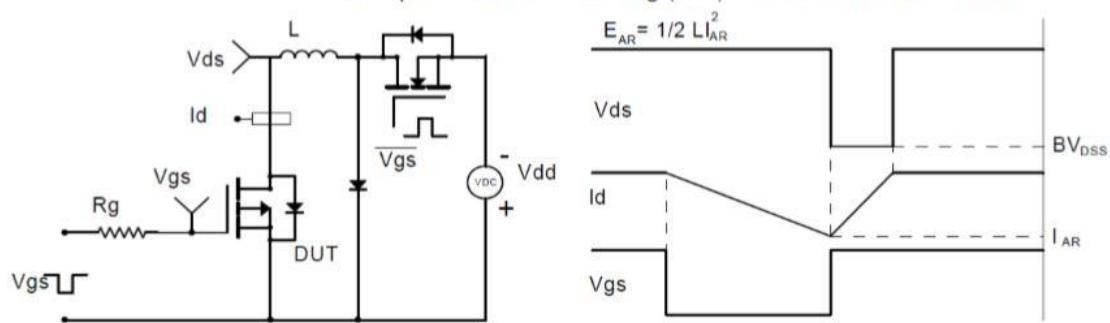
Gate Charge Test Circuit & Waveform



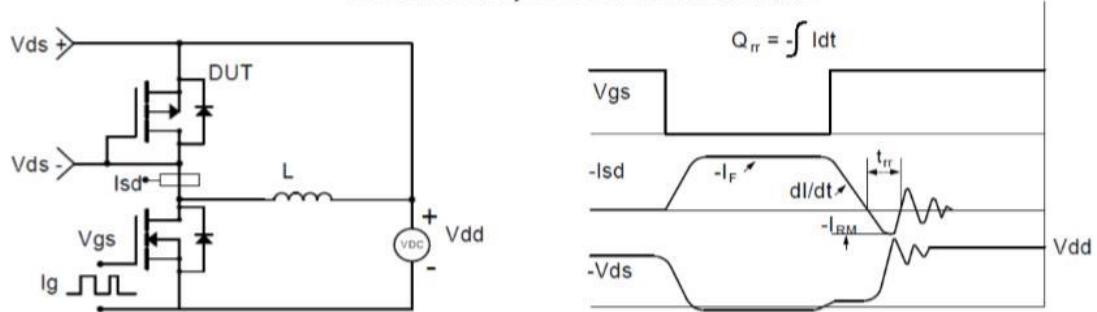
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

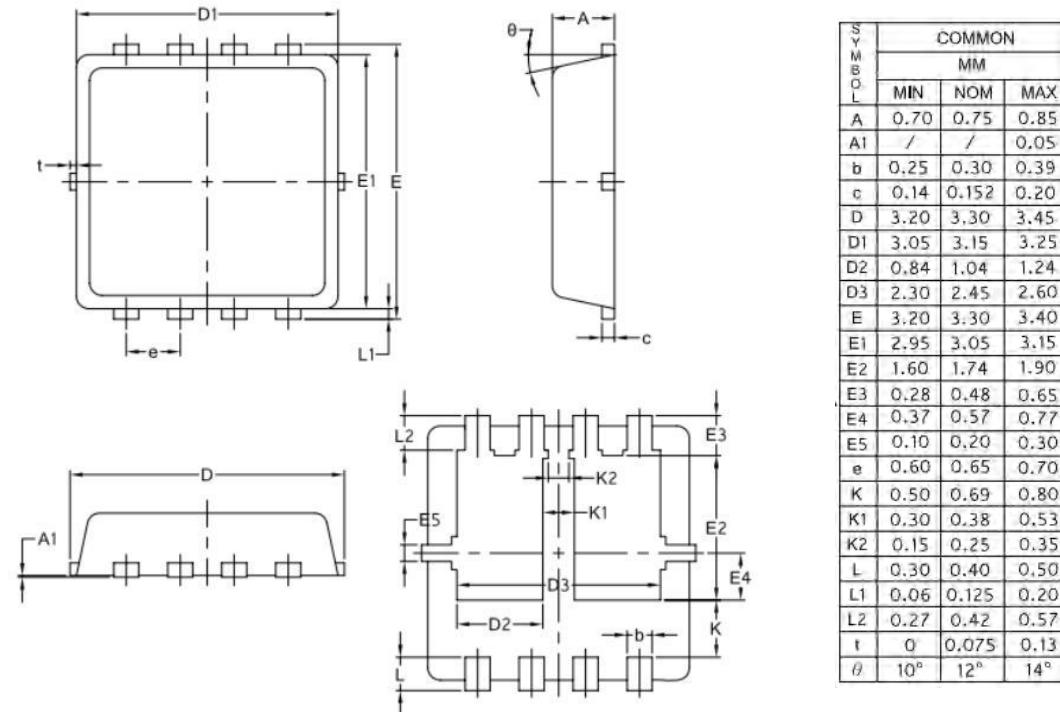


Diode Recovery Test Circuit & Waveforms

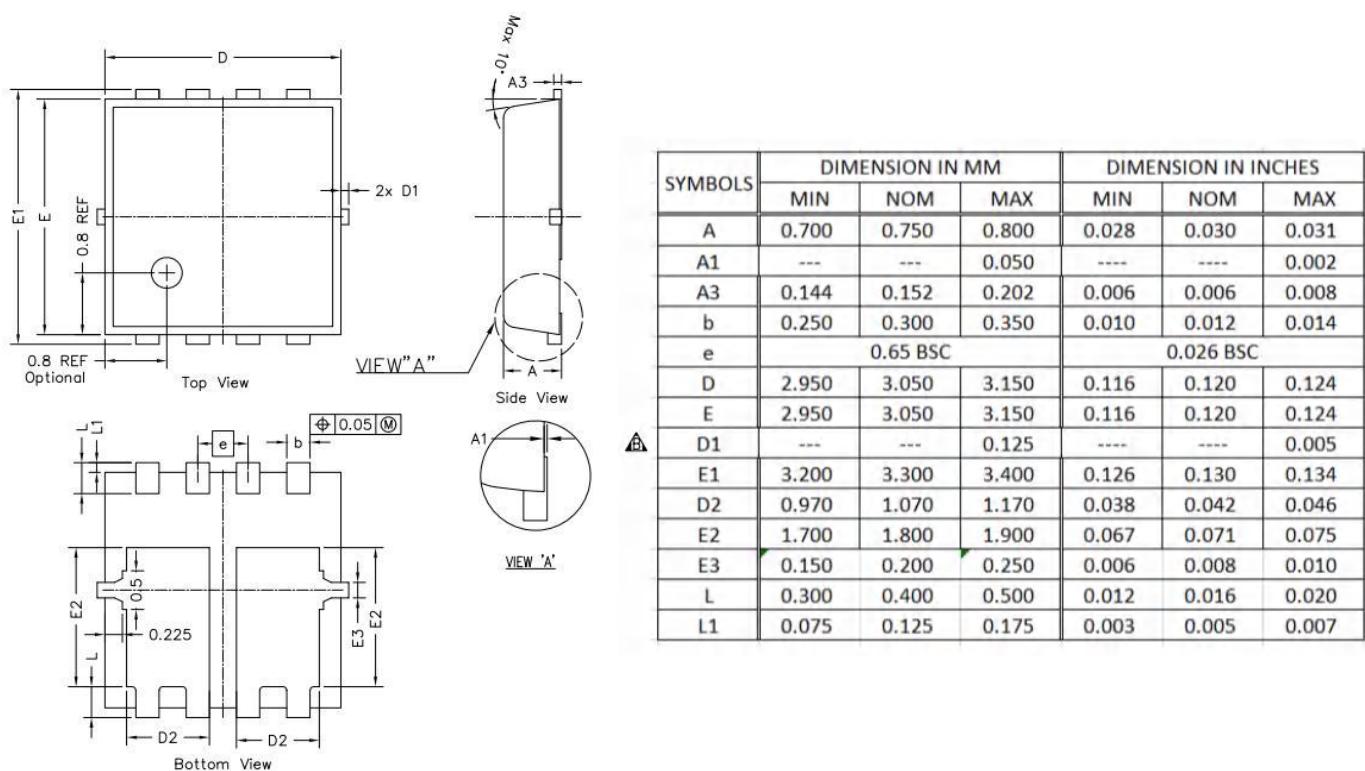




Package Mechanical Data-PDFN3x3-8L-D-Type A



Package Mechanical Data-PDFN3x3-8L-D-Type B





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